

# H-BRIDGE **3020**

#### 4707 Dey Road Liverpool, N.Y. 13088

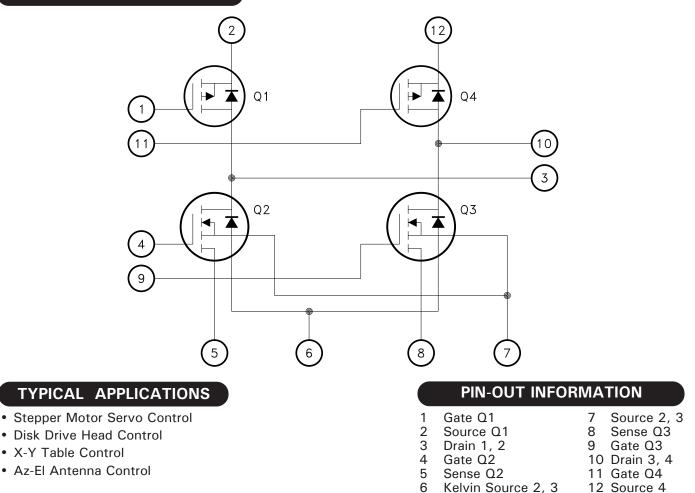
# FEATURES:

- Pin Compatible with MPM3002 and MPM3012
- P and N Channel MOSFETs for Ease of Drive
- N Channel Current Sensing MOSFET for Lossless Sensing
- Isolated Package for Direct Heat Sinking, Excellent Thermal Conductivity
- Avalanche Rated Devices
- 100 Volt, 10 Amp Full H-Bridge

# **DESCRIPTION:**

The MSK 3020 is an H-bridge power circuit packaged in a space efficient isolated ceramic tab power SIP package. The MSK 3020 consists of P-Channel MOSFETs for the top transistors and N-Channel MOSFETs for the bottom transistors. The N Channel MOSFETS are current sensing to allow lossless current sensing for current controlled applications. The MSK 3020 uses M.S. Kennedy's proven power hybrid technology to bring a cost effective high performance circuit for use in today's sophisticated servo motor and disk drive systems. The MSK 3020 is pin compatible with the MPM3002 and MPM3012 with some differences in specifications.

# EQUIVALENT SCHEMATIC





(315) 701-6751

# ABSOLUTE MAXIMUM RATINGS

Vdss	Drain to	Source	Voltage .					.100V	MAX
VDGDR Drain to Gate Voltage									

	$(RGS = 1M\Omega)$
Vgs	Gate to Source Voltage
	(Continuous)±20V MAX
lD	Continuous Current
ldм	Pulsed Current
IM	Sense Current-Continuous
IMM	Sense Current Peak

Single Pulse Avalanche Energy
(Q1,Q4)7.9mJ
(Q2,Q3)69mJ
JunctionTemperature
TJ Storage Temperature
TST Case Operating Temperature Range -55°C to +125°C
Tc Lead Temperature Range
TLD (10 Seconds Lead Only)
RTH-JC Thermal Resistance (Junction to Case)
P-Channel @ 25°C
P-Channel @ 125°C
N-Channel @ 25°C
N-Channel @ 125°C

# ELECTRICAL SPECIFICATIONS

	Task On the A				
Parameter	Test Conditions ④	Min.	MSK 302 Typ.	Max.	Units
Drain-Source Breakdown Voltage	$V_{GS} = 0$ $I_D = 0.25$ mA (All Transistors)	100	-	-	V
Drain-Mirror Breakdown Voltage	$V_{GS} = 0$ $V_{DS} = 100V$ , (Q2, Q3)	100	-	-	V
Drain-Source Leakage Current	VDS = 100V VGS = 0V, (Q2, Q3)	-	-	25	μΑ
-	$V_{DS} = -100V  V_{GS} = 0V, (Q1, Q4)$	-	-	-25	μA
Gate-Source Leakage Current	$V_{GS} = \pm 20V$ $V_{DS} = 0V$ (All Transistors)	-	-	±100	nA
Gate-Source Threshold Voltage	$V_{DS} = V_{GS}$ ID = 250 $\mu$ A (Q2, Q3)	2.0	-	4.0	V
	$V_{DS} = V_{GS}$ ID = 250 $\mu$ A (Q1, Q4)	-2.0	-	-4.0	V
Drain-Source on Resistance ②	$V_{GS} = 10V$ ID = 8.4A (02, 03)	-	-	0.26	Ω
	$V_{GS} = -10V$ ID = -8.4A (Q1, Q4)	-	-	0.31	Ω
Drain-Source on Resistance ③	$V_{GS} = 10V$ ID = 8.4A (02, 03)	-	-	0.16	Ω
	$V_{GS} = -10V$ ID = -8.4A (Q1, Q4)	-	-	0.20	Ω
Forward Transconductance ①	$V_{DS} = 50V$ ID = 8.4A (Q2, Q3)	4.7	-	-	S
	$V_{DS} = -50V$ ID = -8.4A (Q1, Q4)	3.2	-	-	S
N-CHANNEL (Q2, Q3)	ID = 14A			26	nC
Total Gate Charge ①	$V_{DS} = 80V$	-	-	26 5.5	nC nC
Gate-Source Charge ①	$V_{\rm DS} = 00V$ Vgs = 10V	-	-		
Gate-Drain Charge ①	$V_{DD} = 50V$	-	9.5	11	nC
Turn-On Delay Time ① Rise Time ①	VDD = 50V ID = 14A	-	9.5 42	-	nS
	$BG = 12\Omega$	-		-	nS
Turn-Off Delay Time ① Fall Time ①	$R_{D} = 3.5\Omega$	-	22 25	-	nS
Input Capacitance ①	$\frac{\text{HD}}{\text{VGS}} = 0.522$	-	25 700	-	nS
Output Capacitance		-		-	pF
Reverse Transfer Capacitance ①	$V_{DS} = 25V$	-	320	-	pF
Output Capacitance of Sensing Cells ()	f = 1 MHz	-	83	-	pF pF
		1200	9	1540	•
Current Sensing Ratio ① P-CHANNEL (Q1, Q4)	$V_{GS} = 10V ID = 14A$	1390	-	1540	r
Total Gate Charge ①	D = -8.4A	_		58	nC
	$V_{DS} = -80V$	_	-	8.3	nC
Gate-Source Charge ① Gate-Drain Charge ①	VDS = -80V VGS = -10V	_	-	32	nC
Turn-On Delay Time ①	$V_{GS} = -10V$ $V_{DD} = -50V$	_	15	-	nS
Rise Time ①	$I_{\rm D} = -8.4A$	_	58	_	nS
Turn-Off Delay Time ①	$R_{G} = 9.1\Omega$	-	45	-	nS
Fall Time ①	$R_{D} = 6.2\Omega$	_	45 46	-	nS
Input Capacitance ①	$V_{\rm GS} = 0.232$	-	760	-	pF
Output Capacitance (1)	$V_{DS} = -25V$	_	260	-	pF
Reverse Transfer Capacitance (1)	f = 1  MHz	_	170	_	pF
BODY DIODE		-	170		Ы
	$I_{S} = 14A V_{GS} = 0V (02, 03)$	-	2.5	-	V
Forward on Voltage	IS = -14A VGS = 0V (Q1, Q4)	-	-1.6	-	v
	$Is = 14A \text{ di/dt} = 100A/\mu S (Q2, Q3)$	-	150	310	nS
Reverse Recovery Time	$Is = -8.4A \text{ di/dt} = 100A/\mu S (Q1, Q4)$	_	47	71	nS
	-	-			
Reverse Recovery Charge ①	$ls = 14A di/dt = 100A/\mu S (02, 03)$	-	0.85	1.2	μC
	$Is = -8.4A \text{ di/dt} = 100A/\mu S (Q1, Q4)$	-	650	970	nC

### NOTES:

① This parameter is guaranteed by design but need not be tested. Typical parameters are representative of actual device performance but are for reference only.

② Resistance as seen at package pins.

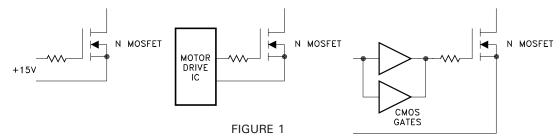
③ Resistance for die only; use for thermal calculations.

④ TA =  $25^{\circ}$ C unless otherwise specified.

# **APPLICATION NOTES**

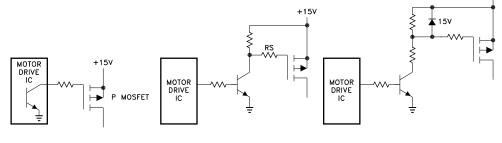
#### N-CHANNEL GATES (Q2, Q3):

For driving the N-Channel gates, it is important to keep in mind that it is essentially like driving a capacitance to a sufficient voltage to get the channel fully on. Driving the gates to +15 volts with respect to their sources assures that the transistors are on. This will keep the dissipation down to a minimum level. How quickly the gate gets turned ON and OFF will determine the dissipation of the transistor while it is transitioning from OFF to ON and vice-versa. Turning the gate ON and OFF too slow will cause excessive dissipation, while turning it ON and OFF too fast will cause excessive switching noise in the system. It is important to have as low a driving impedance as practical for the size of the transistor. Many motor drive IC's have sufficient gate drive capability for the MSK 3020. If not, paralleled CMOS standard gates will usually be sufficient. A series resistor in the gate circuit slows it down, but also suppresses any ringing caused by stray iductances in the MOSFET circuit. The selection of the resistor is determined by how fast the MOSFET wants to be switched. See Figure 1 for circuit details.



#### P-CHANNEL GATES (Q1, Q4):

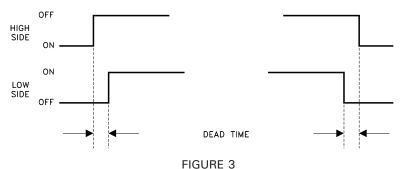
Most everything applies to driving the P-Channel gates as the N-Channel gates. The only difference is that the P-Channel gate to source voltage needs to be negative. Most motor drive IC's are set up with an open collector or drain output for directly interfacing with the P-Channel gates. If not, an external common emitter switching transistor configuration (see Figure 2) will turn the P-Channel MOSFET on. All the other rules of MOSFET gate drive apply here. For high supply voltages, additional circuitry must be used to protect the P-Channel gate from excessive voltages.





#### BRIDGE DRIVE CONSIDERATIONS:

It is important that the logic used to turn ON and OFF the various transistors allow sufficient "dead time" between a high side transistor and its low side transistor to make sure that at no time are they both ON. When they are, this is called "shoot-through" and it places a momentary short across the power supply. This overly stresses the transistors and causes excessive noise as well. See Figure 3.



This deadtime should allow for the turn on and turn off time of the transistors, especially when slowing them down with gate resistors. This situation will be present when switching motor direction, or when sophisticated timing schemes are used for servo systems such as locked antiphase PWM'ing for high bandwidth operation.

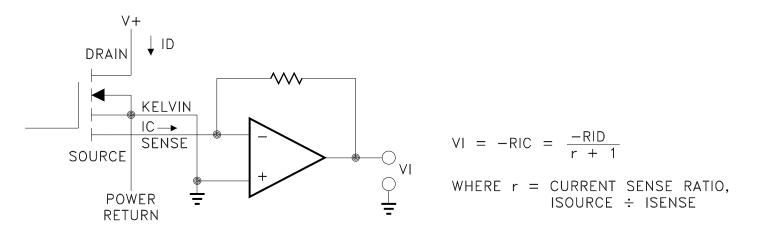
## **APPLICATION NOTES, CONT.**

#### USING CURRENT SENSING MOSFETS:

A MOSFET transistor is constructed of many individual MOSFET cells connected in parallel. They share the current total very evenly. If one of these cells are brought out to a pin, that cell will pass an accurate proportional amount of the total current. This current can be used as a low power sense of the whole current without passing that whole current through a sensing device like a resistor. This small current multiplied by the ratio specified on the data sheet equals the whole current.

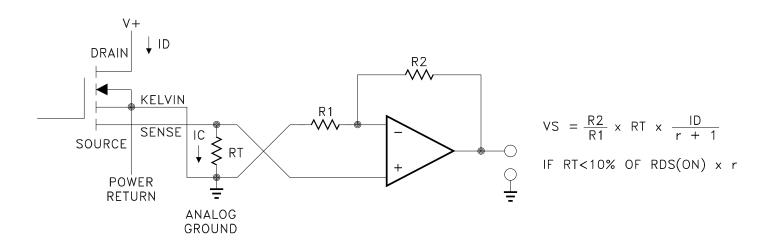
There are several methods of working with the sense function to obtain the actual current.

1. Virtual Earth Sensing



The disadvantage is amplifying a current swing of 10 amps in 100 nSec to produce a 5V output means the op amp has to slew  $50V/\mu$ Sec. This is beyond the capabilities of a lot of op amps.

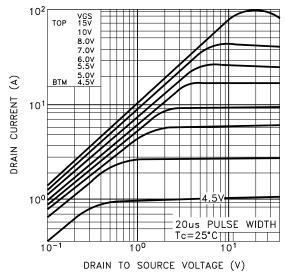
2. Resistor Sensing



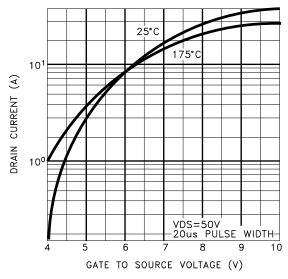
The disadvantage is RT voltage must be above the offset voltage of the op amp and RT must be much less than RDS(ON) of the sensing cell or temperature shifts will affect accuracy.



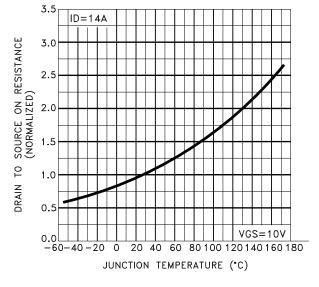
DRAIN CURRENT vs DRAIN TO SOURCE VOLTAGE



DRAIN CURRENT vs GATE TO SOURCE VOLTAGE

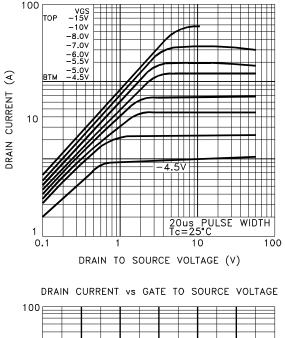


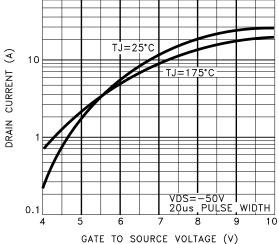
DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMP.



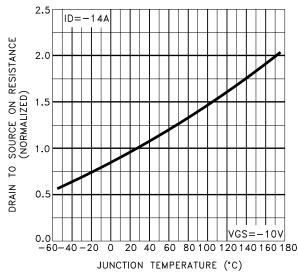
#### P-CHANNEL DEVICES (Q1,Q4)

DRAIN CURRENT vs DRAIN TO SOURCE VOLTAGE

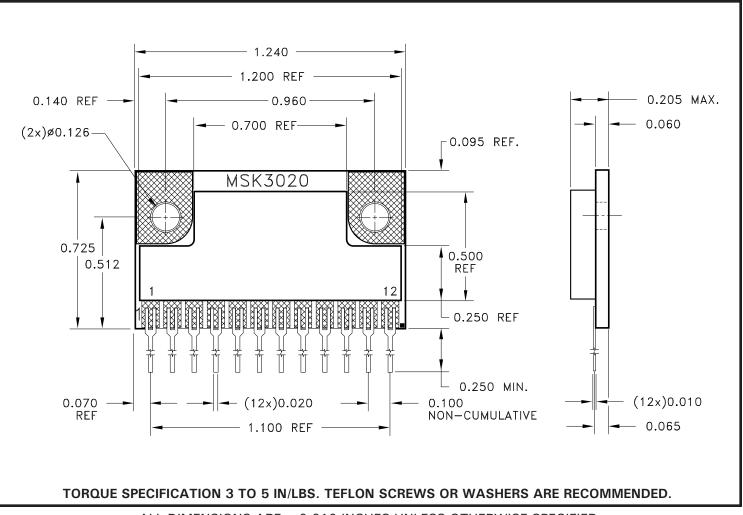




DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMP.



# **MECHANICAL SPECIFICATIONS**



ALL DIMENSIONS ARE ±0.010 INCHES UNLESS OTHERWISE SPECIFIED.

# ORDERING INFORMATION

PART NUMBER	SCREENING LEVEL			
MSK 3020	Industrial			

M.S. Kennedy Corp. 4707 Dey Road, Liverpool, New York 13088 Phone (315) 701-6751 FAX (315) 701-6752 www.mskennedy.com

The information contained herein is believed to be accurate at the time of printing. MSK reserves the right to make changes to its products or specifications without notice, however, and assumes no liability for the use of its products.